

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/076,540 YEE ET AL.	
		Examiner	Art Unit Srirama Channavajjala	2164 Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,201,884	03-2001	Van Bemmel et al.	382/109
	B	US-2002/0128884	09-2002	Heching et al.	705/7
	C	US-6,470,210	10-2002	Chen et al.	600/515
	D	US-5,774,878	06-1998	Marshall, Paul Steven	705/35
	E	US-6,549,820	04-2003	Barrett et al.	700/110
	F	US-6,813,581	11-2004	Snyder, Todd W.	702/130
	G	US-2002/0087389	07-2002	Sklarz et al.	705/10
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP0971321A2	01-2000	European	Gebel,Kai Frank et al.	3/00
	O	WO 00/48101	08-2000	PCT	LUSK,richard	17/60
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Robin Schumascher, "Why you need capacity planning", Database trends and applications, vol 18, number 7, July 2004, 1-2 pages
	V	Hilary K Browne et al. "A trend analysis of exploitations", CS-TR-4200, UMIACS-TR-2000-76, November 9,2000, pp 1-22
	W	Craig S Mullins, "Managing database change", database trends, October 2000, 6 pages
	X	Internet security systems, Inc "trend analysis", server: SYB11, Sybase adaptive server, printed 5/17/00, pp 1-5

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.